

**12A, 60V, 0.150 Ohm, N-Channel Power MOSFETs**

These are N-Channel enhancement mode silicon gate power field effect transistors. They are advanced power MOSFETs designed, tested, and guaranteed to withstand a specified level of energy in the breakdown avalanche mode of operation. All of these power MOSFETs are designed for applications such as switching regulators, switching convertors, motor drivers, relay drivers, and drivers for high power bipolar switching transistors requiring high speed and low gate drive power. These types can be operated directly from integrated circuits.

Formerly developmental type TA49082.

**Ordering Information**

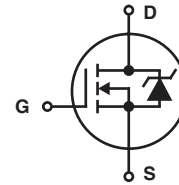
PART NUMBER	PACKAGE	BRAND
RFD3055	TO-251AA	FD3055
RFD3055SM	TO-252AA	FD3055
RFP3055	TO-220AB	FP3055

NOTE: When ordering, use the entire part number. Add the suffix 9A, to obtain the TO-252AA variant in tape and reel, i.e. RFD3055SM9A.

**Features**

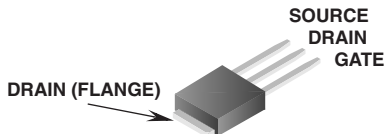
- 12A, 60V
- $r_{DS(ON)} = 0.150\Omega$
- Temperature Compensating PSPICE® Model
- Peak Current vs Pulse Width Curve
- UIS Rating Curve
- 175°C Operating Temperature
- Related Literature
  - TB334 "Guidelines for Soldering Surface Mount Components to PC Boards"

**Symbol**

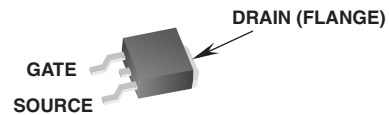


**Packaging**

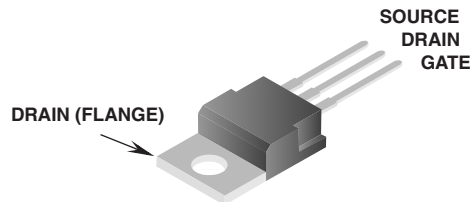
JEDEC TO-251AA



JEDEC TO-252AA



JEDEC TO-220AB



# RFD3055, RFD3055SM, RFP3055

## Absolute Maximum Ratings $T_C = 25^\circ\text{C}$ , Unless Otherwise Specified

	RFD3055, RFD3055SM, RFP3055	UNITS
Drain to Source Voltage (Note 1) . . . . .	$V_{DSS}$	60 V
Drain to Gate Voltage ( $R_{GS} = 20\text{K}\Omega$ ) (Note 1) . . . . .	$V_{DGR}$	60 V
Gate to Source Voltage . . . . .	$V_{GS}$	$\pm 20$ V
Continuous Drain Current . . . . .	$I_D$	12 A
Pulsed Drain Current (Note 3) . . . . .	$I_{DM}$	Refer to Peak Current Curve
Single Pulse Avalanche Rating (Figures 14, 15) . . . . .	$I_{AS}$	Refer to UIS Curve
Power Dissipation . . . . .	$P_D$	53 W
Linear Derating Factor . . . . .		0.357 $\text{W}/^\circ\text{C}$
Operating and Storage Temperature . . . . .	$T_J, T_{STG}$	-55 to 175 $^\circ\text{C}$
Maximum Temperature for Soldering		
Leads at 0.063in (1.6mm) from Case for 10s. . . . .	$T_L$	300 $^\circ\text{C}$
Package Body for 10s, See Techbrief 334 . . . . .	$T_{pkg}$	260 $^\circ\text{C}$

**CAUTION:** Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

**NOTE:**

- $T_J = 25^\circ\text{C}$  to  $150^\circ\text{C}$ .

## Electrical Specifications $T_C = 25^\circ\text{C}$ , Unless Otherwise Specified

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNITS
Drain to Source Breakdown Voltage	$BV_{DSS}$	$I_D = 250\mu\text{A}, V_{GS} = 0\text{V}$ (Figure 11)	60	-	-	V
Gate Threshold Voltage	$V_{GS(TH)}$	$V_{GS} = V_{DS}, I_D = 250\mu\text{A}$ (Figure 10)	2	-	4	V
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = \text{Rated } BV_{DSS}, V_{GS} = 0\text{V}$	-	-	1	$\mu\text{A}$
		$T_C = 125^\circ\text{C}, V_{DS} = 0.8 \times \text{Rated } BV_{DSS}$	-	-	25	$\mu\text{A}$
Gate to Source Leakage Current	$I_{GSS}$	$V_{GS} = \pm 20\text{V}$	-	-	100	nA
Drain to Source On Resistance	$r_{DS(ON)}$	$I_D = 12\text{A}, V_{GS} = 10\text{V}$ (Figure 9) (Note 2)	-	-	0.150	$\Omega$
Turn-On Time	$t_{ON}$	$V_{DD} = 30\text{V}, I_D = 12\text{A}$ $R_L = 2.5\Omega, V_{GS} = +10\text{V}$ $R_G = 10\Omega$ (Figure 13)	-	-	40	ns
Turn-On Delay Time	$t_{d(ON)}$		-	7	-	ns
Rise Time	$t_r$		-	21	-	ns
Turn-Off Delay Time	$t_{d(OFF)}$		-	16	-	ns
Fall Time	$t_f$		-	10	-	ns
Turn-Off Time	$t_{OFF}$		-	-	40	ns
Total Gate Charge	$Q_{g(TOT)}$	$V_{GS} = 0$ to $20\text{V}$	-	19	23	nC
Gate Charge at 10V	$Q_{g(10)}$	$V_{GS} = 0$ to $10\text{V}$				
Threshold Gate Charge	$Q_{g(TH)}$	$V_{GS} = 0$ to $2\text{V}$				
Input Capacitance	$C_{ISS}$	$V_{DS} = 25\text{V}, V_{GS} = 0\text{V},$ $f = 1\text{MHz}$ (Figure 12)	-	300	-	pF
Output Capacitance	$C_{OSS}$		-	100	-	pF
Reverse Transfer Capacitance	$C_{RSS}$		-	30	-	pF
Thermal Resistance Junction to Case	$R_{\theta JC}$		-	-	2.8	$^\circ\text{C}/\text{W}$
Thermal Resistance Junction to Ambient	$R_{\theta JA}$	TO-251 and TO-252	-	-	100	$^\circ\text{C}/\text{W}$
		TO-220	-	-	62.5	$^\circ\text{C}/\text{W}$

## Source to Drain Diode Specifications

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNITS
Source to Drain Diode Voltage	$V_{SD}$	$I_{SD} = 12\text{A}$	-	-	1.5	V
Reverse Recovery Time	$t_{rr}$	$I_{SD} = 12\text{A}, dI_{SD}/dt = 100\text{A}/\mu\text{s}$	-	-	100	ns

**NOTES:**

- Pulse Test: Pulse Width  $\leq 300\text{ms}$ , Duty Cycle  $\leq 2\%$ .
- Repetitive Rating: Pulse Width limited by max junction temperature. See Transient Thermal Impedance Curve (Figure 3) and Peak Current Capability Curve (Figure 5).

Typical Performance Curves Unless Otherwise Specified

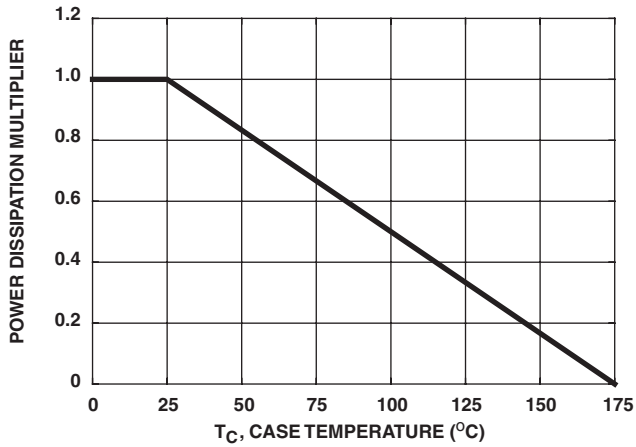


FIGURE 1. NORMALIZED POWER DISSIPATION vs CASE TEMPERATURE

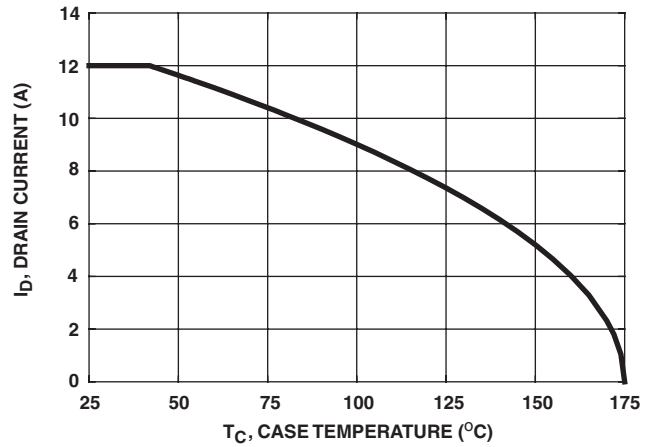


FIGURE 2. MAXIMUM CONTINUOUS DRAIN CURRENT vs CASE TEMPERATURE

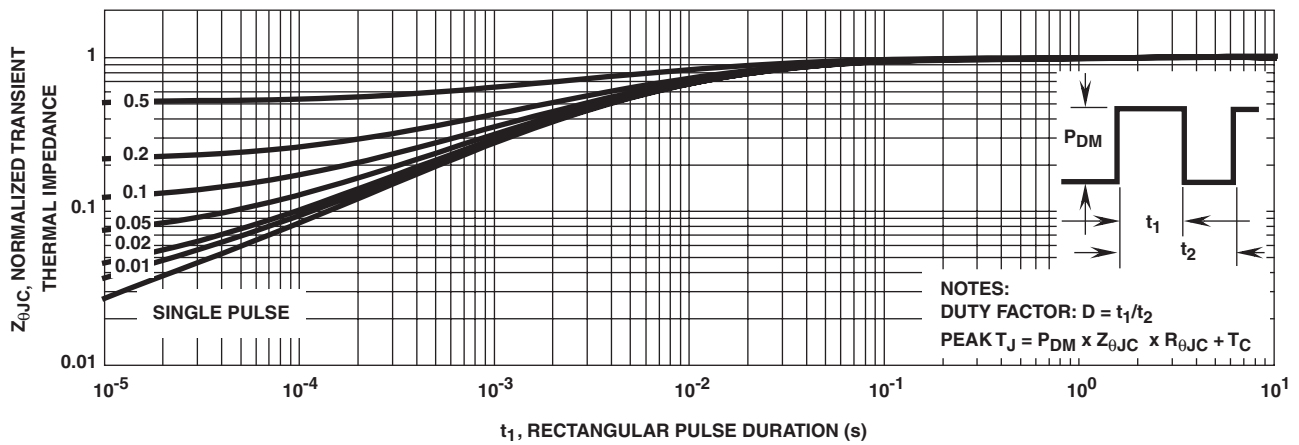


FIGURE 3. NORMALIZED MAXIMUM TRANSIENT THERMAL IMPEDANCE

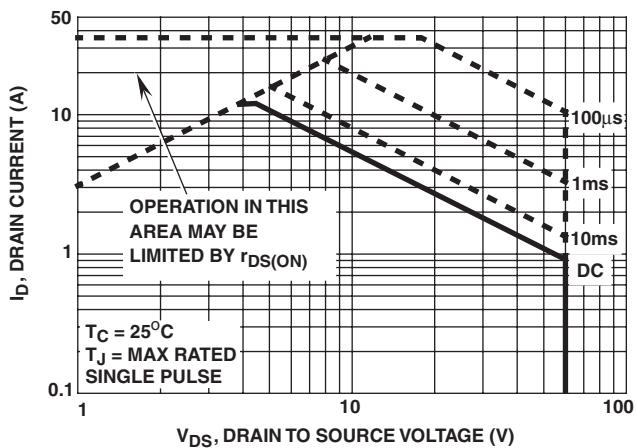


FIGURE 4. FORWARD BIAS SAFE OPERATING AREA

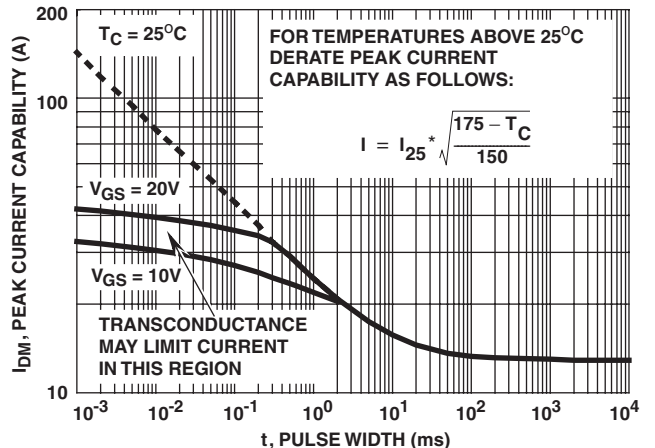


FIGURE 5. PEAK CURRENT CAPABILITY

Typical Performance Curves Unless Otherwise Specified (Continued)

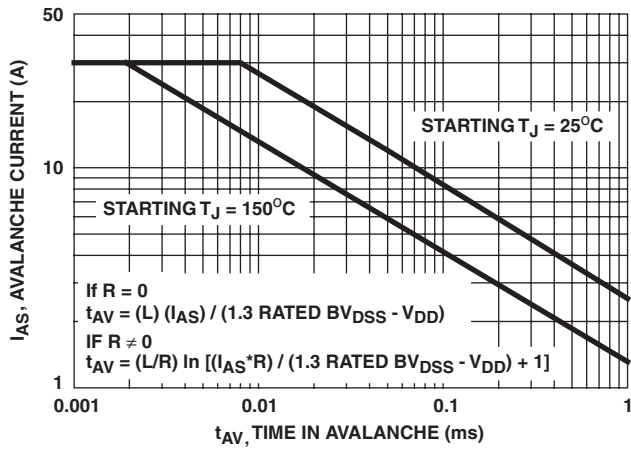


FIGURE 6. UNCLAMPED INDUCTIVE SWITCHING

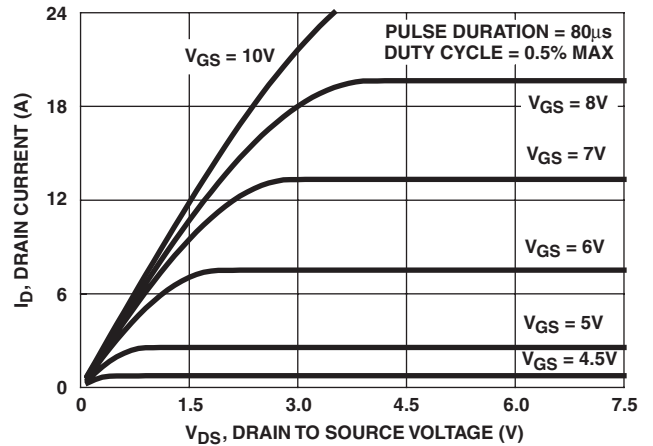


FIGURE 7. SATURATION CHARACTERISTICS

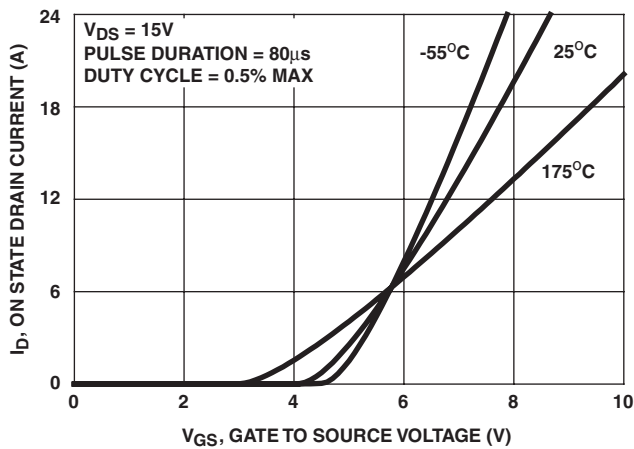


FIGURE 8. TRANSFER CHARACTERISTICS

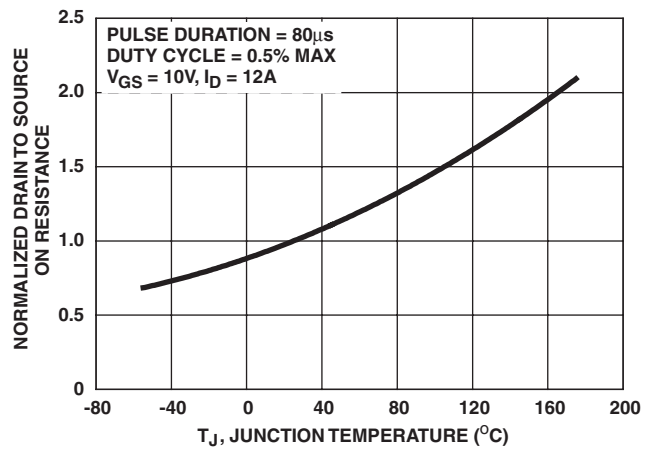


FIGURE 9. NORMALIZED DRAIN TO SOURCE ON RESISTANCE vs JUNCTION TEMPERATURE

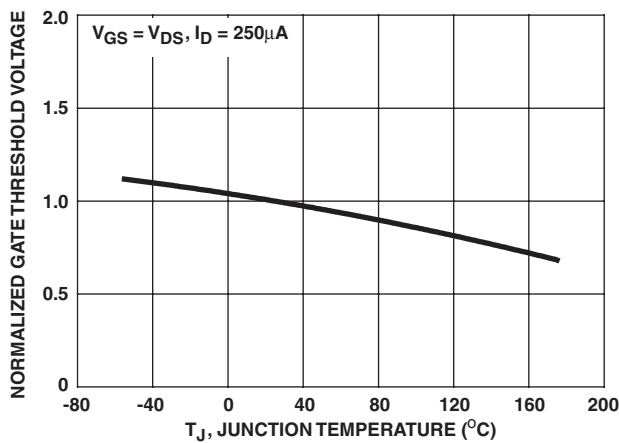


FIGURE 10. NORMALIZED GATE THRESHOLD VOLTAGE vs TEMPERATURE

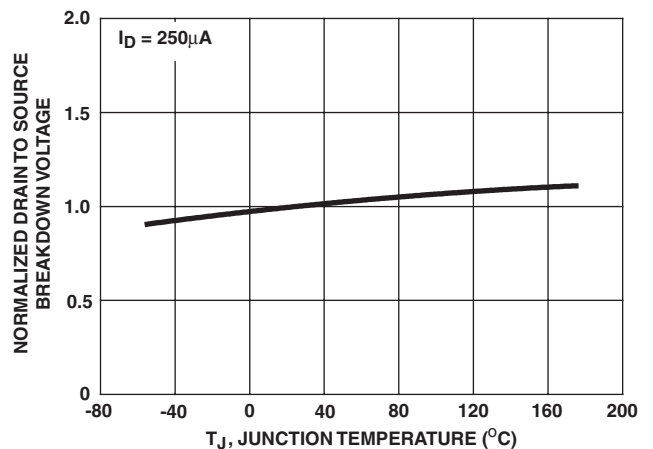


FIGURE 11. NORMALIZED DRAIN TO SOURCE BREAKDOWN VOLTAGE vs TEMPERATURE

**Typical Performance Curves** Unless Otherwise Specified (Continued)

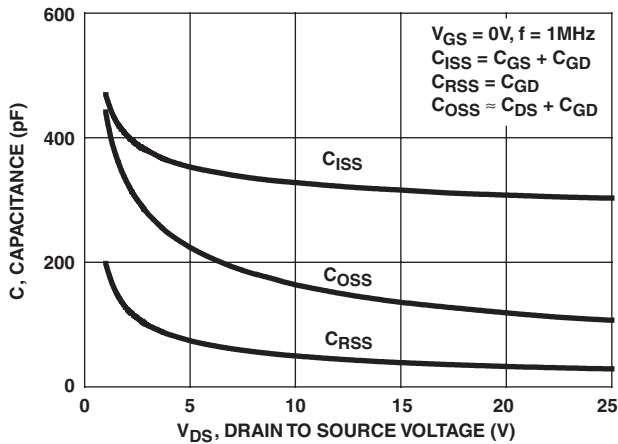
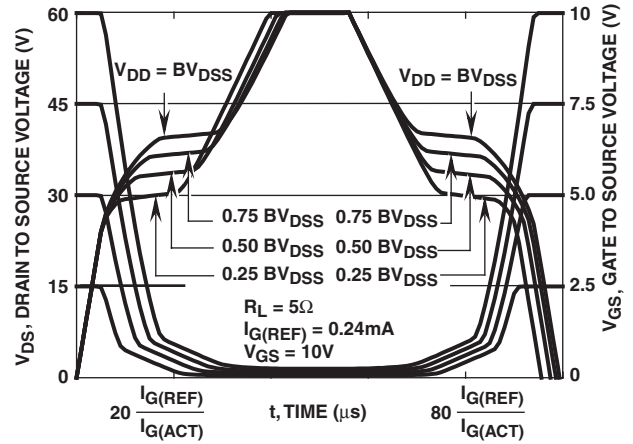


FIGURE 12. CAPACITANCE vs DRAIN TO SOURCE VOLTAGE



NOTE: Refer to Fairchild Application Notes AN7254 and AN7260.

FIGURE 13. NORMALIZED SWITCHING WAVEFORMS FOR CONSTANT GATE CURRENT

**Test Circuits and Waveforms**

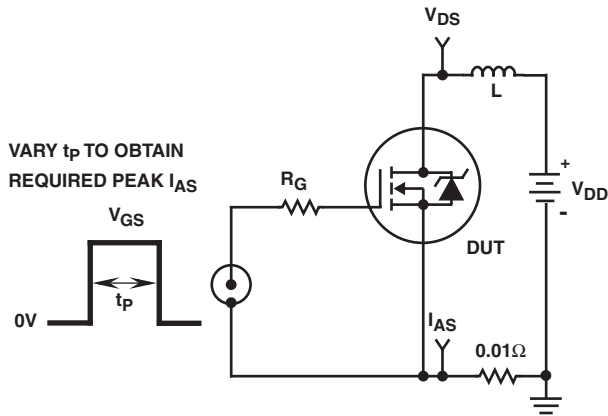


FIGURE 14. UNCLAMPED ENERGY TEST CIRCUIT

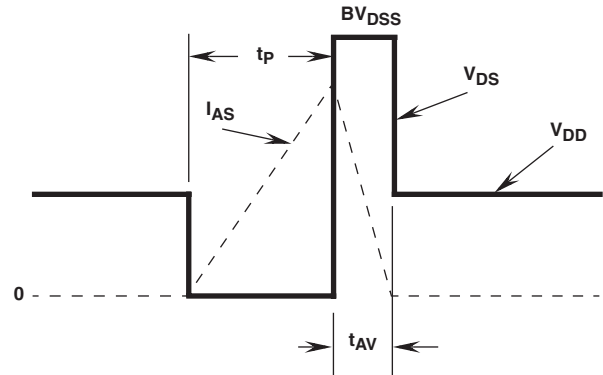


FIGURE 15. UNCLAMPED ENERGY WAVEFORMS

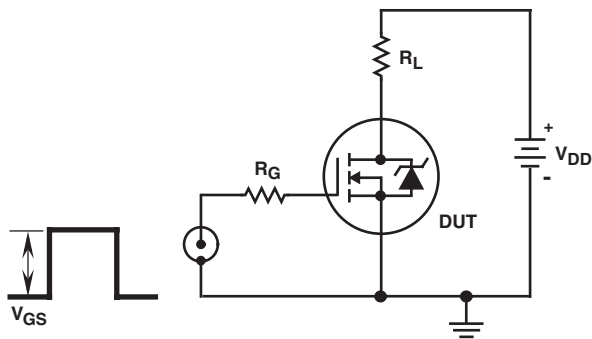


FIGURE 16. SWITCHING TIME TEST CIRCUIT

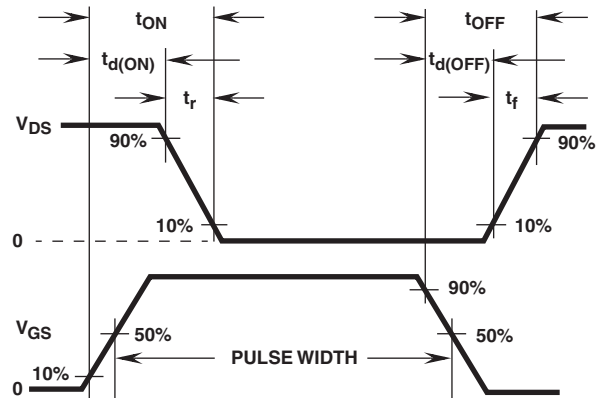


FIGURE 17. RESISTIVE SWITCHING WAVEFORMS

Test Circuits and Waveforms (Continued)

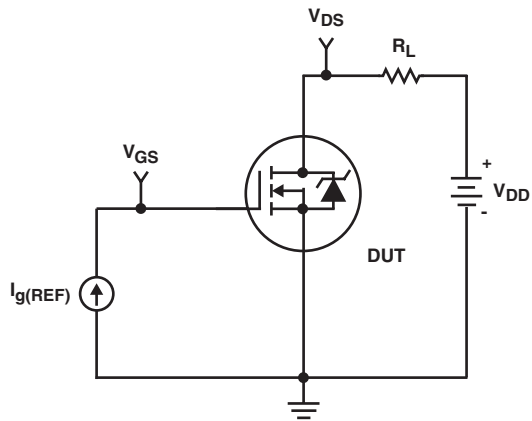


FIGURE 18. GATE CHARGE TEST CIRCUIT

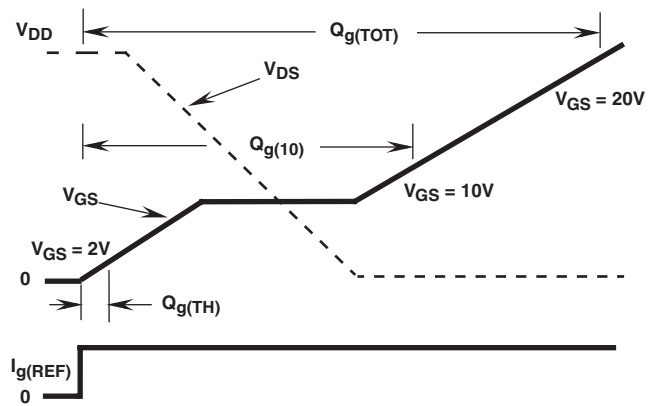


FIGURE 19. GATE CHARGE WAVEFORMS

# RFD3055, RFD3055SM, RFP3055

## PSPICE Electrical Model

.SUBCKT RFP3055 2 1 3; rev 10/26/93

CA 12 8 0.540e-9  
 CB 15 14 0.540e-9  
 CIN 6 8 0.300e-9

DBODY 7 5 DBDMOD  
 DBREAK 5 11 DBKMOD  
 DPLCAP 10 5 DPLCAPMOD

EBREAK 11 7 17 18 67.9  
 EDS 14 8 5 8 1  
 EGS 13 8 6 8 1  
 ESG 6 10 6 8 1  
 EVTO 20 6 18 8 1

IT 8 17 1

LDRAIN 2 5 1e-9  
 LGATE 1 9 4.61e-9  
 LSOURCE 3 7 4.61e-9

MOS1 16 6 8 8 MOSMOD M=0.99  
 MOS2 16 21 8 8 MOSMOD M=0.01

RBREAK 17 18 RBKMOD 1  
 RDRAIN 50 16 RDSMOD 1e-4  
 RGATE 9 20 7.23  
 RIN 6 8 1e9  
 RSCL1 5 51 RSLVCMOD 1e-6  
 RSCL2 5 50 1e3  
 RSOURCE 8 7 RDSMOD 108e-3  
 RVTO 18 19 RVTOMOD 1

S1A 6 12 13 8 S1AMOD  
 S1B 13 12 13 8 S1BMOD  
 S2A 6 15 14 13 S2AMOD  
 S2B 13 15 14 13 S2BMOD

VBAT 8 19 DC 1  
 VTO 21 6 0.5

ESCL 51 50 VALUE={ (V(5,51)/ABS(V(5,51))) \* (PWR(V(5,51)\*1e6/30,6.5)) }

.MODEL DBDMOD D (IS=4.33e-14 RS=2.78e-2 TRS1=1.10e-3 TRS2=5.19e-6 CJO=3.94e-10 TT=7.63e-8)

.MODEL DBKMOD D (RS=0.676 TRS1=1.94e-3 TRS2=-1.09e-6)

.MODEL DPLCAPMOD D (CJO=0.238e-9 IS=1e-30 N=10)

.MODEL MOSMOD NMOS (VTO=4.078 KP=12 IS=1e-30 N=10 TOX=1 L=1u W=1u)

.MODEL RBKMOD RES (TC1=1.06e-3 TC2=-1.92e-6)

.MODEL RDSMOD RES (TC1=5.03e-3 TC2=1.53e-5)

.MODEL RSLVCMOD RES (TC1=2.2e-3 TC2=-5e-6)

.MODEL RVTOMOD RES (TC1=-5.02e-3 TC2=-9.16e-6)

.MODEL S1AMOD VSWITCH (RON=1e-5 ROFF=0.1 VON=-6.5 VOFF=-3.5)

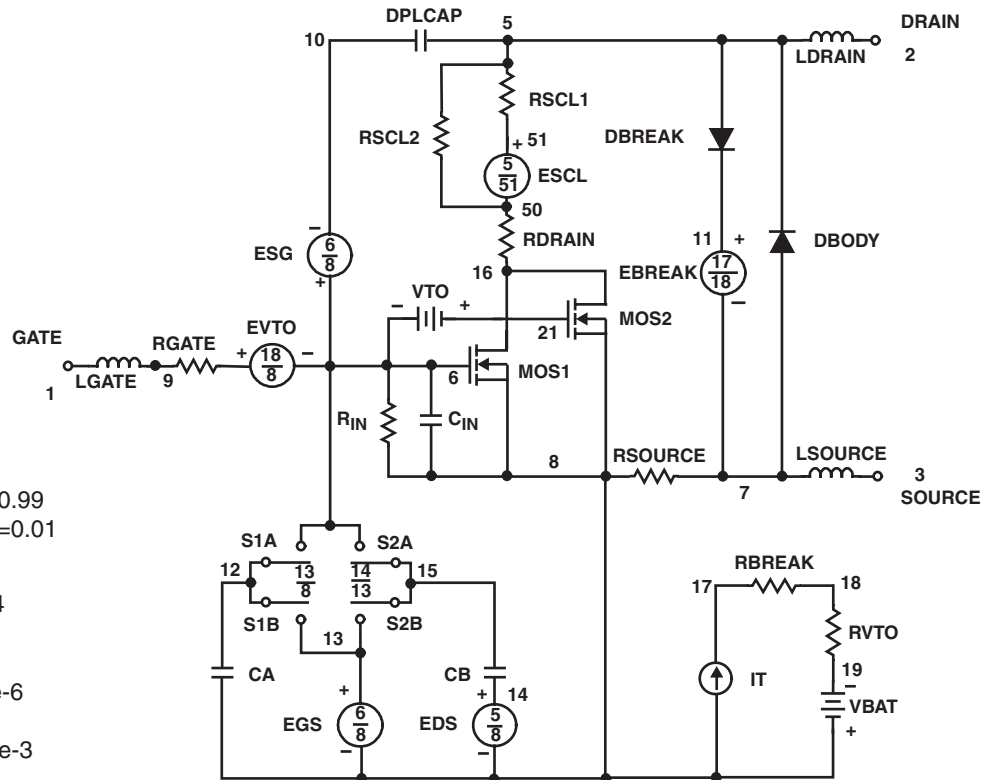
.MODEL S1BMOD VSWITCH (RON=1e-5 ROFF=0.1 VON=-3.5 VOFF=-6.5)

.MODEL S2AMOD VSWITCH (RON=1e-5 ROFF=0.1 VON=-2.50 VOFF=2.50)

.MODEL S2BMOD VSWITCH (RON=1e-5 ROFF=0.1 VON=2.50 VOFF=-2.50)

.ENDS

NOTE: For further discussion of the PSPICE model consult **A New PSPICE Sub-Circuit for the Power MOSFet Featuring Global Temperature Options**; authored by William J. Hepp and C. Frank Wheatley.



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CoolFET <sup>TM</sup>	FRFET <sup>TM</sup>	PACMAN <sup>TM</sup>	Stealth <sup>TM</sup>	
CROSSVOLT <sup>TM</sup>	GlobalOptoisolator <sup>TM</sup>	POP <sup>TM</sup>	SuperSOT <sup>TM</sup> -3	
DenseTrench <sup>TM</sup>	GTO <sup>TM</sup>	Power247 <sup>TM</sup>	SuperSOT <sup>TM</sup> -6	
DOMET <sup>TM</sup>	HiSeC <sup>TM</sup>	PowerTrench <sup>®</sup>	SuperSOT <sup>TM</sup> -8	
EcoSPARK <sup>TM</sup>	ISOPLANAR <sup>TM</sup>	QFET <sup>TM</sup>	SyncFET <sup>TM</sup>	
E <sup>2</sup> CMOS <sup>TM</sup>	LittleFET <sup>TM</sup>	QST <sup>TM</sup>	TinyLogic <sup>TM</sup>	
EnSigna <sup>TM</sup>	MicroFET <sup>TM</sup>	QT Optoelectronics <sup>TM</sup>	TruTranslation <sup>TM</sup>	
FACT <sup>TM</sup>	MicroPak <sup>TM</sup>	Quiet Series <sup>TM</sup>	UHC <sup>TM</sup>	
FACT Quiet Series <sup>TM</sup>	MICROWIRE <sup>TM</sup>	SILENT SWITCHER <sup>®</sup>	UltraFET <sup>®</sup>	

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2. A critical component is any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

## PRODUCT STATUS DEFINITIONS

### Definition of Terms

Datasheet Identification	Product Status	Definition
Advance Information	Formative or In Design	This datasheet contains the design specifications for product development. Specifications may change in any manner without notice.
Preliminary	First Production	This datasheet contains preliminary data, and supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice in order to improve design.
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